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FACSIMILE COVER SHEET

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November 25, 2003

PLEASE DELIVER TO EXAMINER IMMEDIATELY

Receiver:

Examiner Kalimah Fernandez

USPTO

TEL#:

703-305-6310

Telephone: (510) 843-6200

FAX#:

703-746-4847

Sender:

Leslie Russell, Patent Secretary for:

Phillip P. Lee

Re:

U.S. Patent Application: Film Thickness Measurement Using

Facsimile: (510) 843-6203

Electron-Beam Induced X-Ray Microanalysis

Inventor(s): Shing M. Lee Application No.: 09/695,726 File Date: October 23, 2000 Our File No.: KLA1P012

Pages Including Cover Sheet(s): 12

MESSAGE:

Dear Examiner Fernandez:

Attached is a copy of the Amendment E which we mailed to the USPTO on October 2, 2003 (which was before the 3-month deadline). Also attached is a copy of the Postcard stamped received.

Thank you very much for telephone interview conducted today.

Please let us know if you require anything further.

Phillip P. Lee

Registration No. 46,866

CONFIDENTIALITY NOTE

The information contained in this facsimile (FAX) message is legally privileged and confidential information intended only for the use of the receiver or firm named above. If the reader of this message is not the intended receiver, you are hereby notified that any dissemination, distribution or copying of this FAX is strictly prohibited. If you have received this FAX in error, please immediately notify the sender at the telephone number provided above and return the riginal message to the sender at the address above via the United States Postal Service. Thank you.

Docket#	KLA1P012/P647US	By:	PPL/lr	Date of this mailing:	October 2, 2003				
Appl'n#:	09/695,726	Filing Date:	10/23/00						
Inv(s)	Shing M. Lee FILM THICKNESS MEASUREMENT USING ELECTRON-BEAM INDUCED X-RAY MICROANALYSI								
Title:									
The follow	ving have been received in the U.	· · · · · · · · · · · · · · · · · · ·							

Item	Description:	# Pgs
1.	Amendment Transmittal	1
2.	Amendment E	9
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TE:10/21/03 BY:478



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Shing M. Lee

Attorney Docket No.: KLA1P012/P647US

Application No.: 09/695,726

Examiner: Fernandez, K.

Filed: October 23, 2000

Group: 2881

Title: FILM THICKNESS MEASUREMENT

USING ELECTRON-BEAM INDUCED

X-RAY MICROANALYSIS

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA

22313-1450 on October 2, 2003.

AMENDMENT TRANSMIT

Mail Stop Non-Fee Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Transmitted herewith is an Amendment in the above-identified application.

The fee has been calculated as shown below.

	Claims After Amendment		Highest Previously Paid For	Present Extra	Small Entity Rate Fee	Large Entity Rate Fee
Total Claims	22	MINUS	30	00	x9 =	x 18 = 0.00
Independent	03	MINUS	06	00	x 42 =	x 84 = 0.00
Claims	dent Claim Present and Fee Not Previously Paid			ly Paid	\$140.00	\$280.00
Multiple Depe	ncent Claim I I	000011		Total	\$	\$0.00

Applicant(s) believe that no (additional) Extension of Time is required; however, if it is 図 determined that such an extension is required, Applicant(s) hereby petition that such an extension be granted and authorize the Commissioner to charge the required fees for an Extension of Time under 37 CFR 1.136 to Deposit Account No. 500388.

Please charge the required fees, or any additional fees required to facilitate filing the \boxtimes enclosed response, to Deposit Account No. 500388 (Order No. KLA1P012).

Respectfully submitted,

BEYER WEAVER & THOMAS, LLP

Reg. No. 46,866

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